

<b>Notice of References Cited</b>	Application/Control No. 10/750,318		Applicant(s)/Patent Under Reexamination OH ET AL.	
	Examiner Christian Wilson		Art Unit 2891	Page 1 of 1

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	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Beyer, William H., ed., <i>CRC Standard Mathematical Tables and Formulae</i> , CRC Press (1991), pg. 331.
	V	Mayer <i>et al.</i> , <i>Electronic Materials Science: For Integrated Circuits in Si and GaAs</i> , Macmillan (1990), pg. 227-232.
	W	Wolf, <i>Silicon Processing for the VLSI Era: Process Technology</i> , Lattice Press (1986), pg. 323-325.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.